

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination TAKEUCHI ET AL.	
		Examiner Kevin L McHenry	Art Unit 1725	Page 1 of 2

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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Examiner Kevin L McHenry		Art Unit 1725	Page 2 of 2

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